

**Notice of References Cited**

Application/Control No.

10/535,306

Applicant(s)/Patent Under  
Reexamination  
BEGUINOT ET AL.

Examiner

Deborah Yee

Art Unit

1793

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,437,903	03-1984	Furukawa et al.	148/504
	B	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	2000-355735	12-2000	Japan	Junichi Wakita et al.	-----
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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